

### IPC-SM-784

## Guidelines for Chip-on-Board Technology Implementation

ANSI/IPC-SM-784

A standard developed by IPC

#### The Principles of Standardization

In May 1995 the IPC's Technical Activities Executive Committee adopted Principles of Standardization as a guiding principle of IPC's standardization efforts.

#### **Standards Should:**

- Show relationship to Design for Manufacturability (DFM) and Design for the Environment (DFE)
- Minimize time to market
- Contain simple (simplified) language
- Just include spec information
- Focus on end product performance
- Include a feedback system on use and problems for future improvement

#### **Standards Should Not:**

- Inhibit innovation
- Increase time-to-market
- Keep people out
- Increase cycle time
- Tell you how to make something
- Contain anything that cannot be defended with data

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Adopted October 6. 1998

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#### ANSI/IPC-SM-784

# Guidelines for Chip-on-Board Technology Implementation

Developed by the Direct Chip Attachment Task Group of the Hybrid and Related Technologies Committee of IPC

APPROVED DECEMBER 20, 1990 BY



Users of this standard are encouraged to participate in the development of future revisions.

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Any Standard involving a complex technology draws material from a vast number of sources. While the principal members of the Direct Chip Attachment Task Group of the IPC Hybrid and Related Technologies Committee are shown below, it is not possible to include all of those who assisted in the evolution of this standard. To each of them, the members of the IPC extend their gratitude.

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November 1990 IPC-SM-784

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#### **Table of Contents**

1.0	INTRODUCTION
1.1	Scope 1
1.2	Purpose 1
1.3	Applications 1
2.0	REFERENCE DOCUMENTS2
2.1	Institute for Interconnecting and Packaging Electronic Circuits (IPC)
2.2	Electronic Industries Association (EIA) 2
2.3	Department of Defense (DoD)2
2.4	Federal
2.5	American National Standards Institute (ANSI)
2.6	American Society For Testing Materials (ASTM)
2.7	International Society for Hybrid Microelectronics (ISHM)
2.8	Terms and Definitions
3.0	DESIGN OF COB STRUCTURES 6
3.1	System Requirements
3.2	Components
3.3	Printed Boards as P&I Structures 10
3.4	Thermal Issues
3.5	Design for Manufacturability

4.0	ASSEMBLY OF COB STRUCTURES	. 19
4.1	Chip and Wire	. 19
4.2	Tape Automated Bonding (TAB)	. 32
4.3	Flip-Chip (Controlled Collapse) Bonding	. 33
4.4	Polymer Bonding Techniques	. 34
5.0	DEVICE PROTECTION FOR COB STRUCTURES	. 35
5.1	Passivation	. 35
5.2	Chip Passivation	. 35
5.3	Dispensing	. 36
5.4	Overmolding	. 36
6.0	REWORK AND REPAIR OF COB STRUCTURES	. 36
6.0 7.0	QUALIFICATION TESTING FOR COB	
	COB STRUCTURES	. 37
<b>7.0</b> 7.1	QUALIFICATION TESTING FOR COB ASSEMBLIES	. 37 . 37
7.0	QUALIFICATION TESTING FOR COB ASSEMBLIES Electrical Characteristics	. 37 . 37
<b>7.0</b> 7.1 7.2	QUALIFICATION TESTING FOR COB ASSEMBLIES  Electrical Characteristics  Mechanical Integrity	. 37 . 37 . 37
<b>7.0</b> 7.1 7.2 7.3	QUALIFICATION TESTING FOR COB ASSEMBLIES  Electrical Characteristics  Mechanical Integrity  Functional Reliability	. 37 . 37 . 37 . 37

November 1990